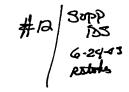
Approved for use through 10/31/2002. OMB 0651-0032
U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE to a collection of information unless it displays a valid OMB control number.

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|---|-----------------------------|-----------------------|-------------|--------------|--|
| FEE TRANSMITTAL | Application Number | | | Numb | 20/252 222 |
| | Filing Date | | | | May 11, 2001 |
| for FY 2002 | | | | d Inver | |
| Patent fees are subject to annual revision. | | Exam | | | William D. Coleman |
| Auglieut deine well auft status Con 27 CFR 4 27 | | | | | |
| Applicant claims small entity status. See 37 CFR 1.27 | | Group | | | 2823 |
| TOTAL AMOUNT OF PAYMENT (\$) 180.00 | Attomey Docket No. | | | ocket No | o. M4065.0743/P743 |
| METHOD OF PAYMENT (check all that apply) | FEE CALCULATION (continued) | | | | |
| Check X Credit Money Order Other None X Deposit Account | 3. # | ADDITIO | ONAL | . FEES | 3 |
| Deposit | | e Entity | | II Entity | _ |
| Account Number 04-1073 | Fee Code | Fee (\$) | Fee Code | Fee (\$) | Fee Description Fee Paid |
| Deposit Account Dickstein Shapiro Morin & | 105 | 130 | 205 | 65 | Surcharge – late filing fee or oath |
| Name Oshinsky LLP The Commissioner is hereby authorized to: (check all that apply) | 127 | 50 | 227 | 25 | Surcharge – late provisional filing fee or cover sheet. |
| Charge fee(s) indicated below X Credit any overpayments | 139 | 130 | 139 | 130 | Non-English specification |
| X Charge any additional fee(s) during the pendency of this application | 147 | 2,520 | 147 | 2,520 | For filing a request for ex parte reexamination |
| Charge fee(s) indicated below, except for the filing fee | 112 | 920* | 112 | 920* | Requesting publication of SIR prior to Examiner action |
| to the above-identified deposit account. | 113 | 1,840* | 113 | 1,840* | Requesting publication of SIR after Examiner action |
| FEE CALCULATION | 115 | 110 | 215 | 55 | Extension for reply within first month |
| 1. BASIC FILING FEE | 116 | 400 | 216 | 200 | Extension for reply within second month |
| Large Entity Small Entity | 117 | 920 | 217 | 460 | Extension for reply within third month |
| Fee Fee Fee Fee Fee Description Fee Paid | 118 | 1,440 | 218 | 720 | Extension for reply within fourth month |
| 101 740 201 370 Utility filing fee | 128 | 1,960 | 228 | 980 | Extension for reply within fifth month |
| 106 330 206 165 Design filing fee | 119 | 320 | 219 | 160 | Notice of Appeal |
| 107 510 207 255 Plant filing fee 108 740 208 370 Reissue filing fee | 120 121 | 320 280 | 220 221 | 160 | Filing a brief in support of an appeal |
| 108 740 208 370 Reissue filing fee 114 160 214 80 Provisional filing fee | 138 | 1,510 | 138 | 140 1,510 | Request for oral hearing Petition to institute a public use proceeding |
| · | 140 | 110 | 240 | 55 | Petition to revive – unavoidable |
| SUBTOTAL (1) (\$) 0.00 | 141 | 1,280 | 241 | 640 | Petition to revive - unintentional Utility issue fee (or reissue) |
| 2. EXTRA CLAIM FEES FOR UTILITY AND REISSUE | 142 | 1,280 | 242 | 640 | Utility issue fee (or reissue) |
| Extra Fee from Fee Paid Claims below Fee Paid | 143 | 460 | 243 | 230 | Design issue fee |
| Total Claims -** = x = x | 144 | 620 | 244 | 310 | Plant issue fee |
| Independent Claims -** = X = = | 122 | 130 | 122 | 130 | |
| Multiple Dependent = | 123 | 50 | 123 | 50 | Processing fee under 37 CFR 1.17(|
| Large Entity Small Entity | 126 | 180 | 126 | 180 | Submission of Information Disclosure 5tmt 180.00 |
| Fee Fee Fee Code (\$) Fee Description | 581 | 40 | 581 | 40 | Recording each patent assignment per property (times number of properties) |
| 103 18 203 9 Claims in excess of 20 | 146 | 740 | 246 | 370 | Filing a submission after final rejection (37 CFR 1.129(a)) |
| 102 84 202 42 Independent claims in excess of 3 104 280 204 140 Multiple dependent claim, if not paid | 149 | 740 | 249 | 370 | For each additional invention to be examined (37CFR 1.129(b)) |
| 109 84 209 42 ** Reissue independent claims | 179 | 740 | 279 | 370 | Request for Continued Examination (RCE) |
| over original patent | 169 | 900 | 169 | 900 | Request for expedited examination |
| 110 18 210 9 ** Reissue claims in excess of 20 and over original patent | | fee (spe | l | | of a design application |
| SUBTOTAL (2) (\$) 0.00 *Reduced by Basic Filing Fee Paid SUBTOTAL (3) (\$) 180.00 **or number previously paid, if greater; For Reissues, see above | | | | | |
| SUBMITTED BY | | | | | Complete (if applicable) |
| Name (Print/Type) Thomas J. D'Amic | | ration No ey/Agent | | 3,371 | Telephone (202) 828-2232 |
| Signature | | | | | Date May 22, 2003 |
| | | | | | |





Docket No.: M4065.0743/P743

(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of: Steven T. Harshfield, et al

Application No.: 09/853,233

Group Art Unit: 2823

Filed: May 11, 2001

Examiner: William D. Coleman

For:

PCRAM MEMORY CELL AND METHOD OF MAKING SAME

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT (IDS)

Commissioner for Patents Washington, DC 20231

Dear Sir:

Pursuant to 37 CFR 1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO/SB/08. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is filed more than three months after the U.S. filing date, OR more than three months after the date of entry of the national stage of a PCT application, AND after the mailing date of the first Office Action on the merits, whichever occurs first, but before the mailing date of a Final Rejection or Notice of Allowance.

A brief explanation of relevance of the non-patent documents listed on form PTO/SB/08 is provided and attached hereto as Appendix A. Additionally, specific

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portions of one patent and two U.S. patent publications cited on the attached form are pointed out in Appendix A. The brief explanation provided for each document is not tantamount to an admission that a document is "material" or that it qualifies as prior art. The Examiner is respectfully requested to utilize Appendix A only as a tool by which to better categorize the documents for substantive use in examining the claims of the application.

Documents discussed in Appendix A marked with an asterisk (*) are indicated to be potentially more relevant than others. Such marking is provided only to assist the Examiner; however, the Examiner is requested to thoroughly review all documents cited herein.

In accordance with 37 C.F.R. § 1.97(g), the filing of this Information Disclosure Statement shall not be construed to mean that a search has been made or that no other material information as defined in 37 C.F.R. § 1.56(a) exists. It is submitted that the Information Disclosure Statement is in compliance with 37 C.F.R. § 1.98 and the Examiner is respectfully requested to consider and cite the listed documents.

Please charge our Credit Card in the amount of \$180.00 covering the fee set forth in 37 CFR 1.17(p). Credit Card Payment Form SB-2038, with a signature from an authorized cardholder, is enclosed. The Commissioner is hereby authorized to charge any deficiency in the fees filed, asserted to be filed or which should have been filed herewith (or

with any paper hereafter filed in this application by this firm) to our Deposit Account No. 04-1073, under Order No. M4065.0743/P743.

Dated: May 22, 2003

Respectfully submitted,

Thomas J. D'Amico

Registration No.: 28,371

DICKSTEIN SHAPIRO MORIN &

OSHINSKY LLP

2101 L Street NW

Washington, DC 20037-1526

(202) 785-9700

Attorneys for Applicant

APPENDIX A

*Kozicki, U.S. Patent No. 6,487,106 (2002): this patent discloses two embodiments shown in Figs. 2 and 3 which include a barrier layer 250, 350, respectively, formed between the layer of conductive material (such as chalcogenide material) 240, 340, respectively and the electrode 230, 330, respectively. (See col. 5, lns. 12-24; col. 7, lns. 7-17). Fig. 5 discloses a structure 502 including an amorphous silicon diode 570 formed adjacent to electrode 520, and a contact 560 formed adjacent the amorphous silicon diode 570.

Kozicki et al., U.S. Patent Application Publication No. 2002/0190350: this publication discloses in Figs. 5A, 6, 8 and 9 a structure having a substrate 510, 610, 810, 910; an insulating layer 520, 620, 820, 920; a bottom electrode 530, 630, 830, 930; an ion conductor 540, 640, 840, 940; a dielectric layer 550, 650, 850, 950; and a top electrode 560, 660, 860, 960. Fig. 5B discloses a structure having a bottom electrod 530, an ion conductor 540, an amorphous diode 562, and a top electrode 560.

*Moore et al., U.S. Patent Application Publication No. 2003/0001229: this publication discloses in Fig. 8 a memory cell structure comprising a substrate 12, a dielectric layer 14, a first metal layer 16, a second metal layer 18, a metal-doped chalcogenide layer 27, another dielectric layer 17, an insulating layer 30, and an electrode 32. First metal layer 16 may be made from tungsten (paragraph 20) and the second metal layer 18 may be silver (paragraph 21).

*Moore et al., U.S. Patent Application Publication No. 2002/0127886: this publication discloses in Fig. 6 a memory cell structure comprising a substrate 10, an insulating layer 11, a conductive layer 12, a metal layer 31, a glass material layer 51, and an electrode 61. Conductive layer 12 may be made from tungsten (paragraph 17) and the metal layer 31 may be silver (paragraph 19).

Moore et al., U.S. Patent Application Publication No. 2002/0123170: this publication discloses in Fig. 6 a memory cell structure which includes a substrate 10, an insulating layer 11, a conductive material 12, a dielectric layer 13, a metal ion-laced glass material 51, a layer of metal material 41, and an electrode 61.

*Kozicki, U.S. Patent Application Publication No. 2003/0035314: this publication discloses a barrier layer 250, 350 as shown in Figs. 2 and 3 and discussed in paragraphs 35 and 45, respectively, formed between the layer of conductive material (such as chalcogenide material) 240, 340, respectively and the electrode 230, 330, respectively. Fig. 5 discloses a structure 502 including an amorphous silicon diode 570 formed adjacent to electrode 520, and a contact 560 formed adjacent the amorphous silicon diode 570, as discussed in paragraph 59.

*Kozicki, U.S. Patent Application Publication No. 2003/0035315: paragraph 70 on page 7 and Fig. 1 disclose a contact 165 electrically coupled to electrode 120, and which may be formed of tungsten. Paragraph 82 on page 8 and Fig. 4 disclose a structure 400 including an amorphous silicon diode 470 formed adjacent to electrode 420, and a contact 460 formed adjacent the amorphous silicon diode 470. Paragraph 102 on page 11 and Figs. 27-28 disclose a common electrode 2710, ion conductors 2730 and 2735, second electrodes 2720 and 2725, and an insulating layer 2750. The insulating layer 2750 is a dielectric layer "that does not interfere with surface electrodeposit growth, such as silicon oxides, silicon nitrides, and the like."

*Helbert et al., SPIE Vol. 333 Submicron Lithography (1982): this publication generally relates to, <u>inter alia</u>, hybrid ultragraphic process using both electron beam and conventional optical exposure within the same device level with a photoresist.

*Kozicki et al., Superlattices and Microstructures, 27 (2000): this publication generally relates to, <u>inter alia</u>, solid solutions of metals (e.g., silver) in arsenic trisulfide and their physical and electrical characteristics.

*Kozicki et al., Microelectronic Engineering, vol. 63/1-3 (2002): this publication generally relates to, inter alia, the photodiffusion of Ag into germanium selenide glass films, the amount of Ag that can be incorporated in to such a film by photodiffusion, and the characteristics of the resulting doped films.

*Kozicki et al., Proceedings of the 1999 Symposium on Solid State Ionic Devices (1999): this publication generally relates to, <u>inter alia</u>, physical and electrical characteristics of metal doped chalcogenide films (photodoped Ag₄As₂S₃) between electrodes, useful in memories, configurable connections, and self-repairing interconnections.

*Kozicki and Mitkova, Proceedings of the XIX International Congress on Glass, Society for Glass Technology (2001): this publication generally relates to, inter alia, the physical effects of introduction of Ag into chalcogenide glasses, where introduction is by photodiffusion.